

V _{DSS}	-60V
R _{DS} (on)	23m
I _D	-26A

I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	-26	^
I_{DM}	Pulsed Drain Current	-60	Α Α
P _D @T _C = 25°C	Power Dissipation	60	W
V _{DS}	Drain-Source Voltage	-60	V
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy @ L=0.5mH	125	mJ
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C

R _{JC}	Junction-to-case	2.0	/W

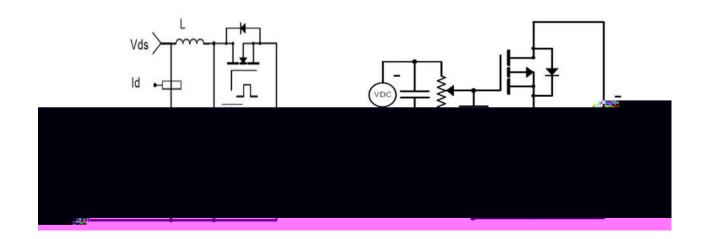


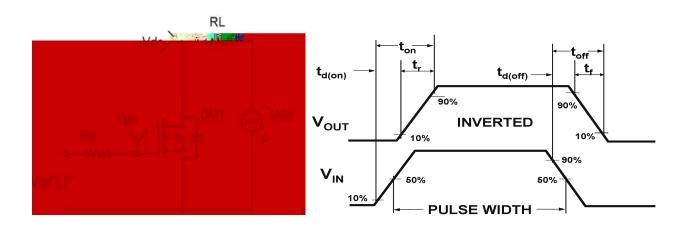
$@T_A=25$ unless otherwise specified

V _{(BR)DSS}	Drain-to-Source breakdown voltage	-60	_	_	V	$V_{GS} = 0V, I_{D} = -250\mu A$
R _{DS(on)} Static Drain-to-So	0 5 0	_	23	30	m	V _{GS} =-10V, I _D =-18A
	Static Drain-to-Source on-resistance	_	29	40		V _{GS} =-4.5V, I _D =-10A
V _{GS(th)}	Gate threshold voltage	-1	_	-2.5	V	$V_{DS} = V_{GS}$, $I_D = -250 \mu A$
I _{DSS}	Drain-to-Source leakage current	_	_	-1	μΑ	V _{DS} =-60V,V _{GS} = 0V
	Cote to Course forward looks as	_	_	100	A	V _{GS} =20V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -20V
Qg	Total gate charge	_	48	_		V _{DS} =-30V
Q _{gs}	Gate-to-Source charge		11	_	nC	I _D =-20A
Q_{gd}	Gate-to-Drain("Miller") charge	_	10	_		V _{GS} =-10V
t _{d(on)}	Turn-on delay time	_	27	_		V _{DS} =-30V
t _r	Rise time	_	31	_		V _{GS} =-10V
t _{d(off)}	Turn-Off delay time	_	60	_	ns	R _{GEN} =3
t f	Fall time		33	_		I _D =-1A
Ciss	Input capacitance	_	3010	_		V _{GS} = 0V
Coss	Output capacitance	_	150	_	pF	V _{DS} = -30V
Crss	Reverse transfer capacitance	_	128	_		f = 1MHz

l.	Continuous Source Current			-26	A	MOSFET symbol □ •
Is (Be	(Body Diode)		_	-26		showing the
1.	Pulsed Source Current			60	۸	integral reverse G → +
ISM	I _{SM} (Body Diode) —	_	-60	A	p-n junction diode.	
V _{SD}	Diode Forward Voltage	_	_	-1.2	V	I _S =-1A, V _{GS} =0V
trr	Reverse Recovery Time	_	40	_	ns	L = 201 di/dt=1001/up
Qrr	Reverse Recovery Charge	_	56	_	nC	I _S =-20A,di/dt=100A/us

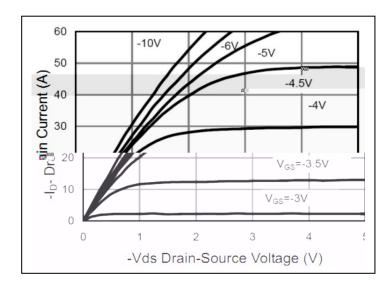


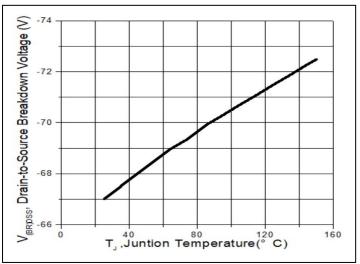


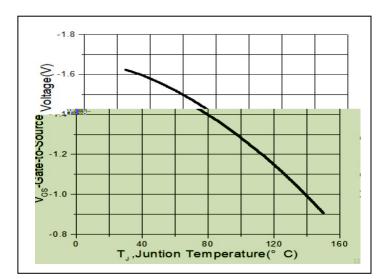


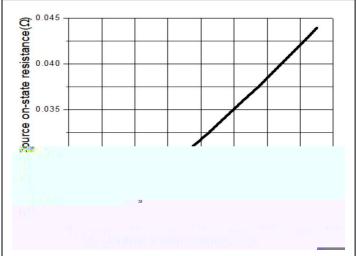
Calculated continuous current based on maximum allowable junction temperature.
Repetitive rating; pulse width limited by max. junction temperature.
The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.

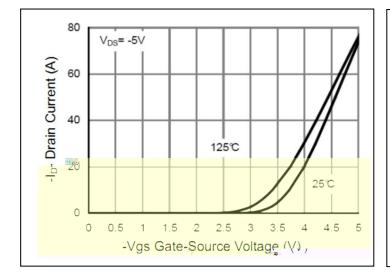


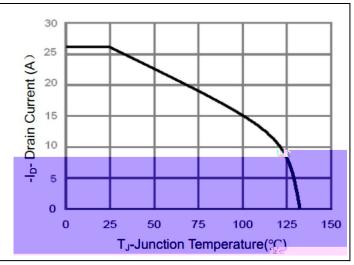




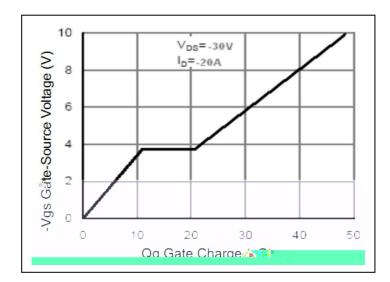


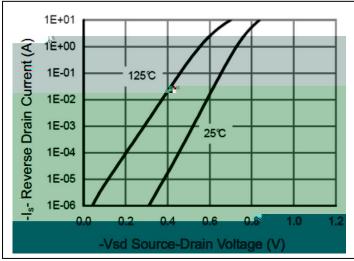


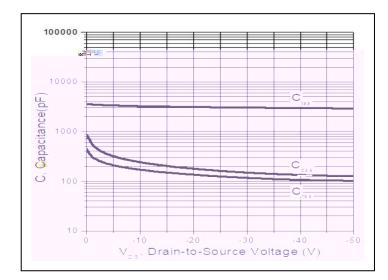




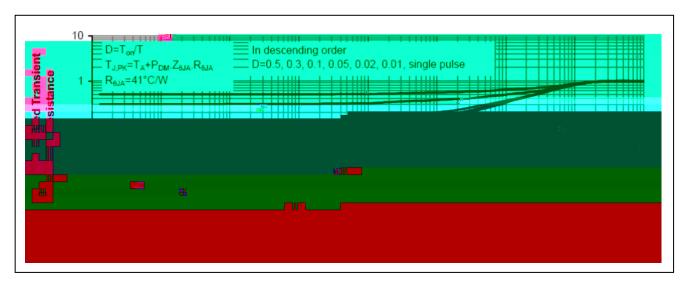




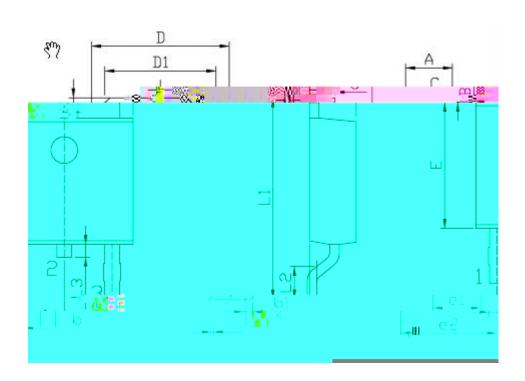








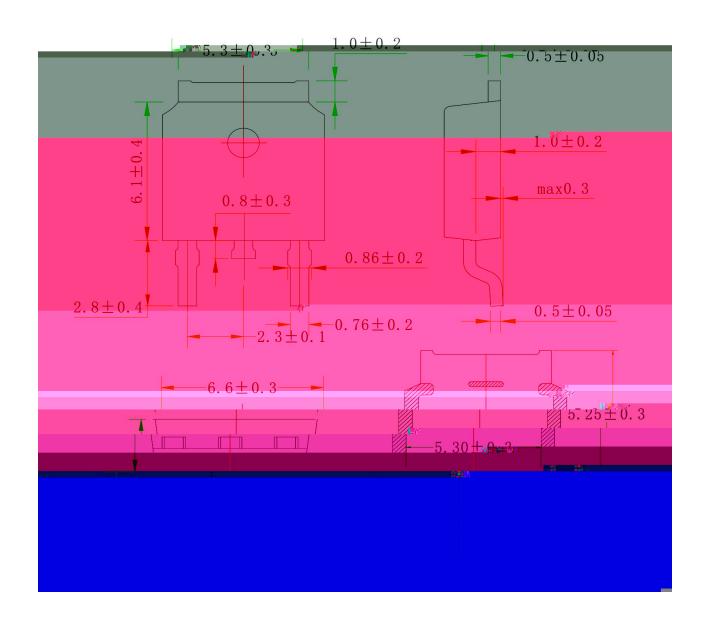




单位: mm

Symbol	Dimensions In Millimeters		Symbol -	Dimensions In Millimeters		
Зушоот	Min	Max	Зушьот	Min	Max	
A	2.20	2. 40	Е	5. 95	6. 25	
B	.0. 95	L 25	e	2.21	2.31	
Ь	0, 50	0.90	e2	1. 13	1.73	
Ы	0 15	0.55	11,	9 15	G GS.	







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